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assembly is retrieved. The loading data (CAD data) defines which component is placed at which position and at what angle of rotation. On the basis of this information and taking into consideration the object resolution, it is possible for each recorded X-ray image to determine precisely where a soldered joint of a component is shown in the X-ray image.

IN THE CLAIMS

Please amend the claims as follows (Marked-up copies of the amended claims are attached as an Appendix):

14. (Amended) A device for inspecting at least one test object comprising:
an X-ray beam tube having a small field of view in relation to a horizontal extent of an area of the at least one test object to be inspected; and
a detector having a small field of view in relation to the horizontal extent of the area of the at least one test object to be inspected,
C2 wherein the at least one test object is fixed in a stationary position throughout the inspection, and said X-ray beam tube and said detector are linearly moveably arranged within parallel X-Y planes for inspecting an entire area of the at least one test object.

15. (Amended) The device in accordance with claim 14, further comprising a carrier adapted to be fixedly mounted throughout the inspection of the at least one test object, wherein said carrier is coupled to the at least one test object during the inspection.

16. (Amended) The device in accordance with claim 14, further comprising a computing device being coupled to said detector.

32. (Amended) A process of inspecting at least one test object with an apparatus that includes an X-ray beam tube having a small field of view in relation to a horizontal extent of an area of the test objects to be inspected, and a detector having a small field of view in relation to the horizontal extent of the area of the test objects to be inspected, the process comprising:

fixedly mounting the at least one test object in a stationary position throughout the inspecting of an entire area of the at least one object; and

linearly moving the X-ray beam tube and the detector within parallel X-Y planes, thereby inspecting the entire area of the at least one test object.

33. (Amended) The process in accordance with claim 32, further comprising linearly moving the X-ray beam tube and the detector parallel to each other.

34. (Amended) The process in accordance with claim 33, further comprising linearly moving the X-ray beam tube and the detector together in a same direction.

35. (Amended) The process in accordance with claim 33, further comprising linearly moving the X-ray beam tube and the detector a same direction.

36. (Amended) The process in accordance with claim 33, further comprising linearly moving the X-ray beam tube and the detector in opposite directions.

37. (Amended) The process in accordance with claim 32, further comprising linearly moving the X-ray beam tube and the detector parallel to the at least one test object.